

<b>Notice of References Cited</b>	Application/Control No. 09/769,890	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner John L Shew	Art Unit 2664	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,784,573 A	07-1998	Szczepanek et al.	709/250
	B	US-6,564,280 B1	05-2003	Walsh, James J.	710/305
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Claims For Application Serial No. 09/769890
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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